

VeEX® Announces Issuance of U.S. Patent Covering OFDM Subcarrier Scan Measurements

Fremont, Calif., March 11, 2021 - [VeEX Inc.](http://www.veexinc.com), a global leader in innovative test and measurement solutions for next-generation networks, is pleased to announce that the United States Patent and Trademark Office has recently issued U.S. Patent No. 10,756,778, 'Systems and Methods for Subcarrier Scan.'

Subcarrier Scan is a core piece of VeEX's industry leading portfolio of DOCSIS 3.1 OFDM field analyzers, including its [CX310](#), [CX380C](#), [CX380s-D3.1](#) and [AT2500-3G](#) models. One of the key benefits of Subcarrier Scan is its powerful, in-depth graphical depiction of OFDM subcarrier data, including Power, MER, and Noise, which enables cable operators to identify hidden interference residing in the same spectrum as OFDM channels.

"Over the past few years of DOCSIS 3.1 deployment, our key MSO customers have benefited from our easy-to-use OFDM Analysis measurements," said Steve Kim, Director of Product Marketing at VeEX. "Our patented Subcarrier Scan measurement has proven to be effective, helping to verify solid OFDM signal transmission, as well as resolving mystifying impairment issues."

About VeEX

VeEX Inc., a customer-oriented communications test and measurement company, develops innovative test and monitoring solutions for next generation telecommunication networks and services. With a blend of advanced technologies and vast technical expertise, VeEX products address all stages of network deployment, maintenance, field service turn-up, and integrate service verification features across copper, fiber optics, CATV/DOCSIS, mobile 4G/5G backhaul and fronthaul, next generation transport network, Fibre Channel, carrier & metro Ethernet technologies, WLAN and synchronization. Learn more at www.veexinc.com.